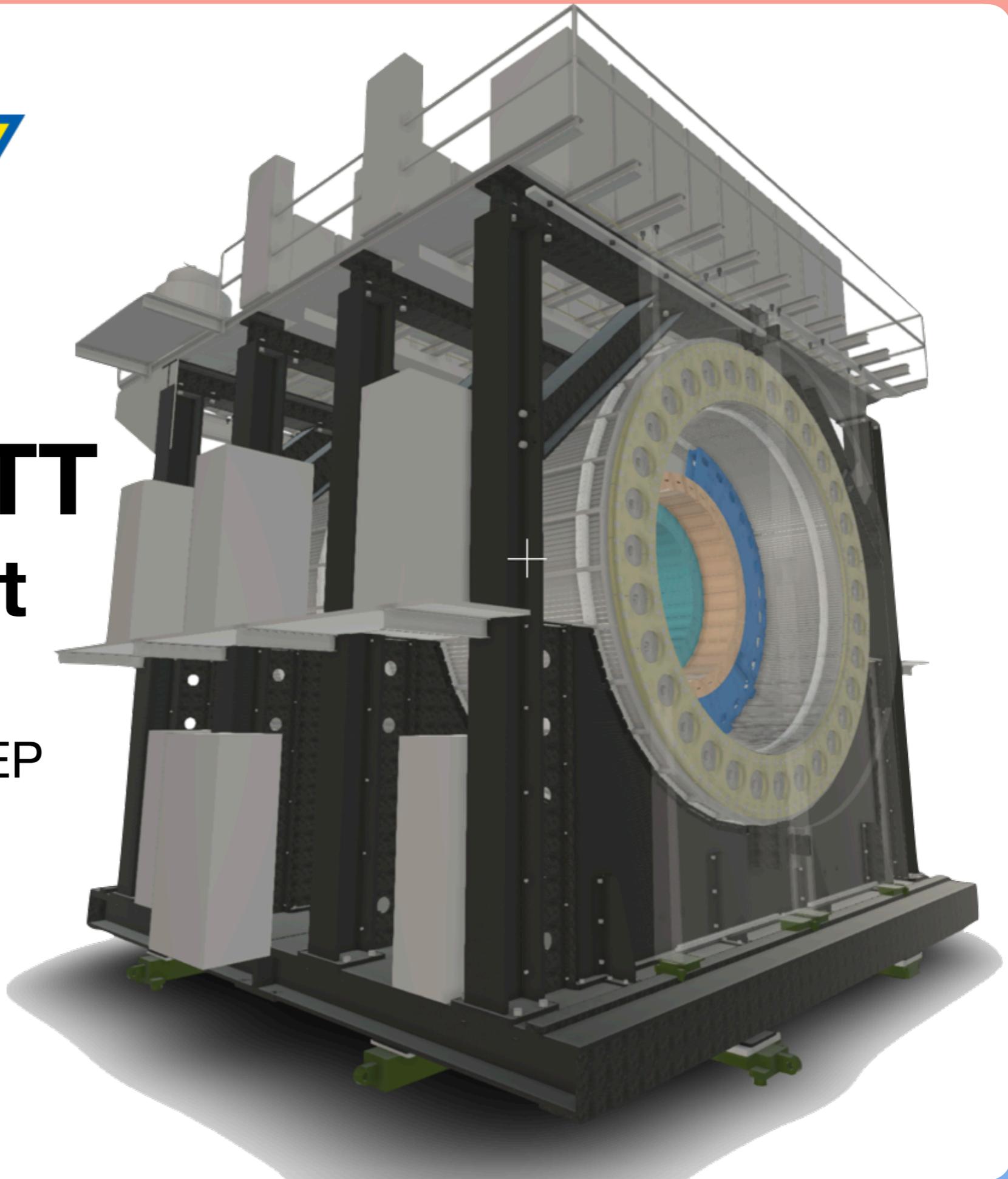




SPHENIX INTT - Weekly Report

Cheng-Wei Shih, NCUHEP

2021/5/20

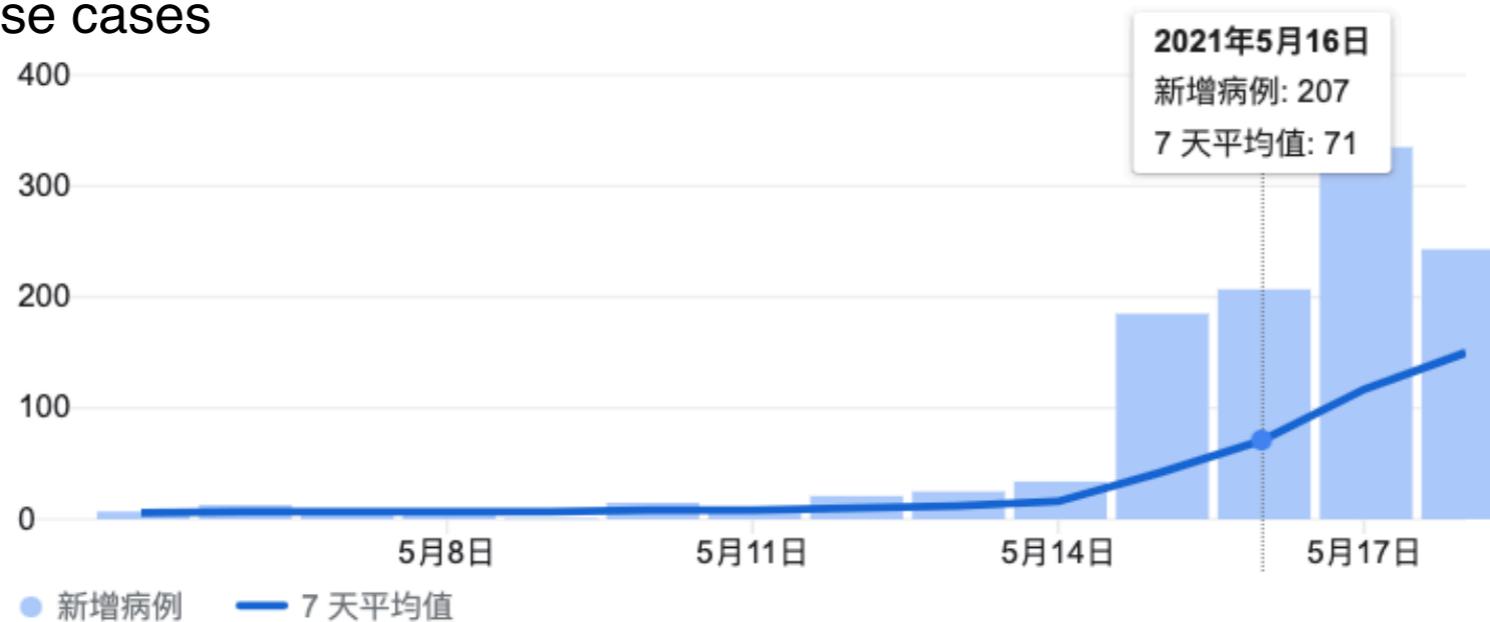


COVID-19 status in Taiwan



- ~ 250 new COVID-19 cases each day.
 - Most of the cases are from Taipei.
- CDC raised epidemic warning to level 3 nationwide.
 - Indoor gathering < 5 people.
 - We stop to go to NTU for 1 week so far.

Increase cases



Half-ladder assembly status



Half-ladder assembly

	Total	Good	Not yet bonded & tested	Bad
Chip to HDI	11	1	0	10
Sensor to HDI	4	2	1	1
Encapsulation	3	3	0	0
Thermal cycle	34	30	0	4

One in NWU

all bonded	29
1 ~ 6 un-bonded	7
7 ~ 25 un-bonded	0
> 25 un-bonded	3

Bonding performance (chip to sensor)

Stave quality test

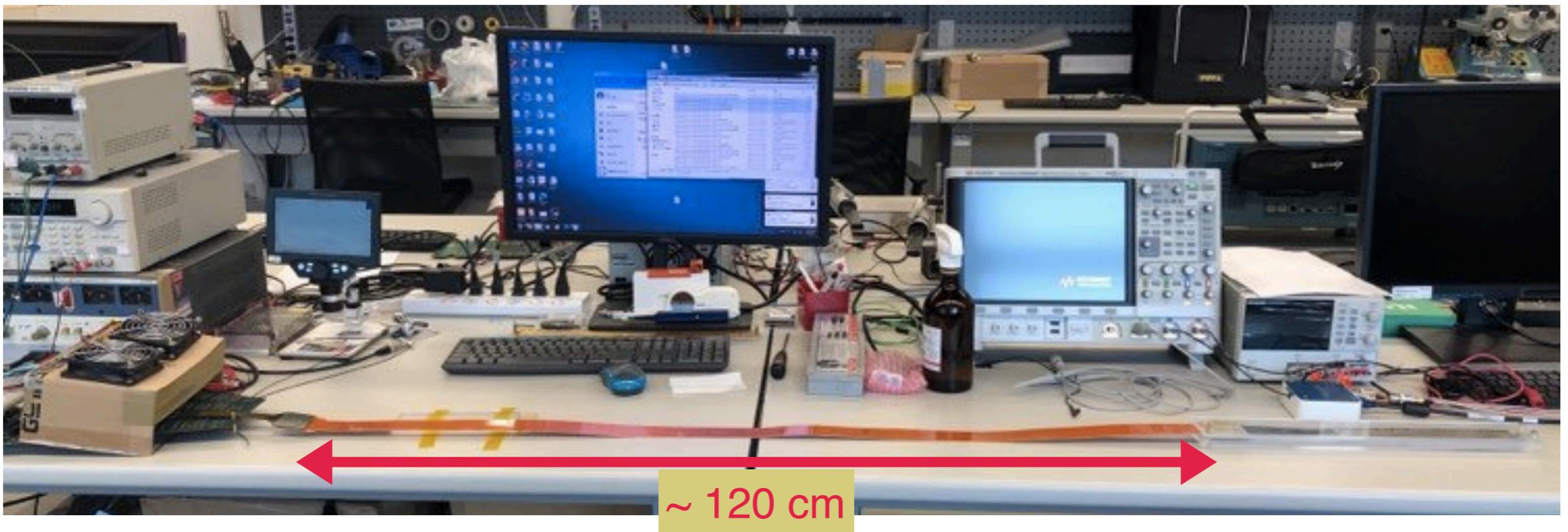


- Tube clamp + torque screwdriver from BNL is arrived.
- We have DP460NS on hand now
- We haven't used it yet, we need instructions from BNL.

Components arrival : BEC

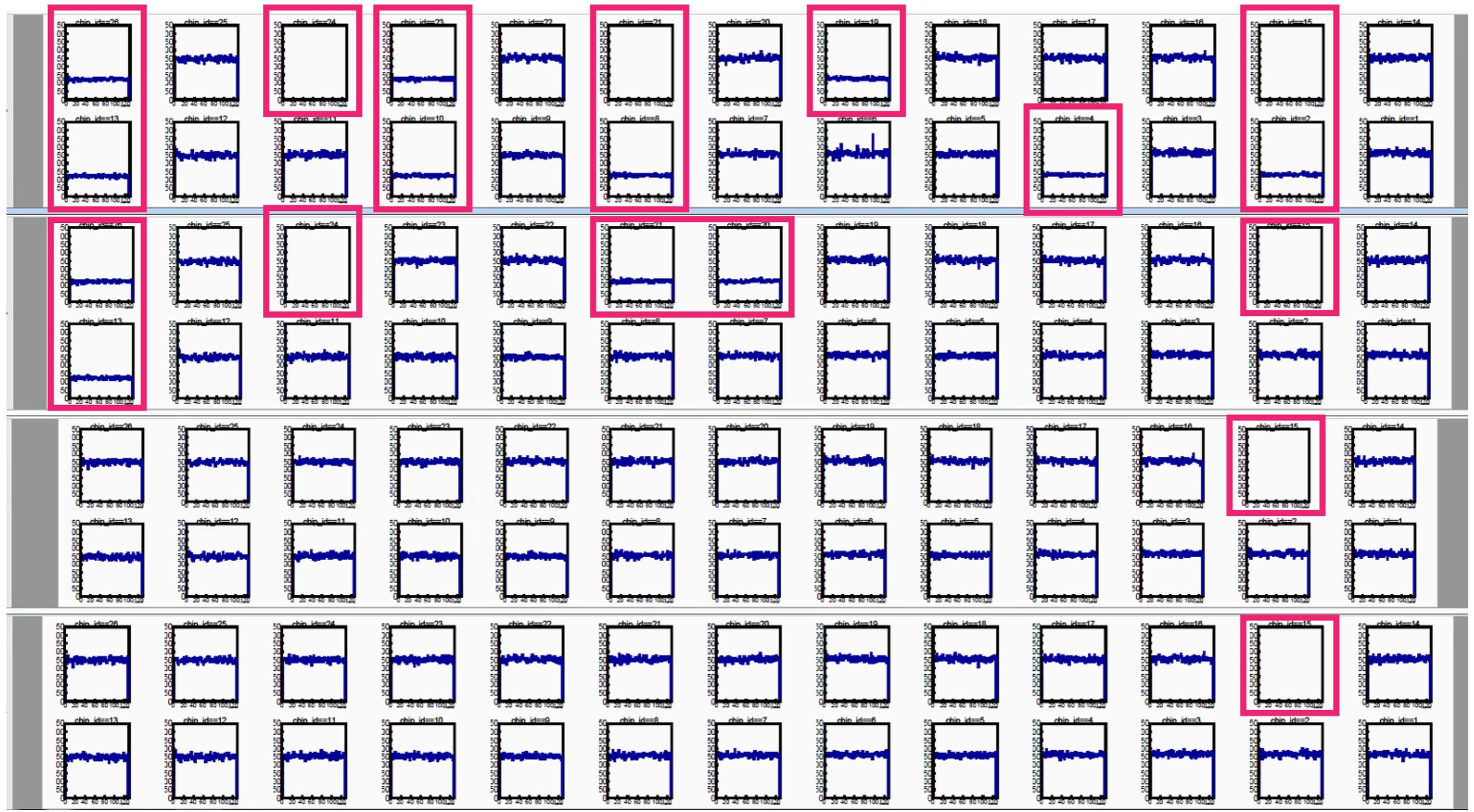


- 2 Bus Extender Cables from NWU were arrived.



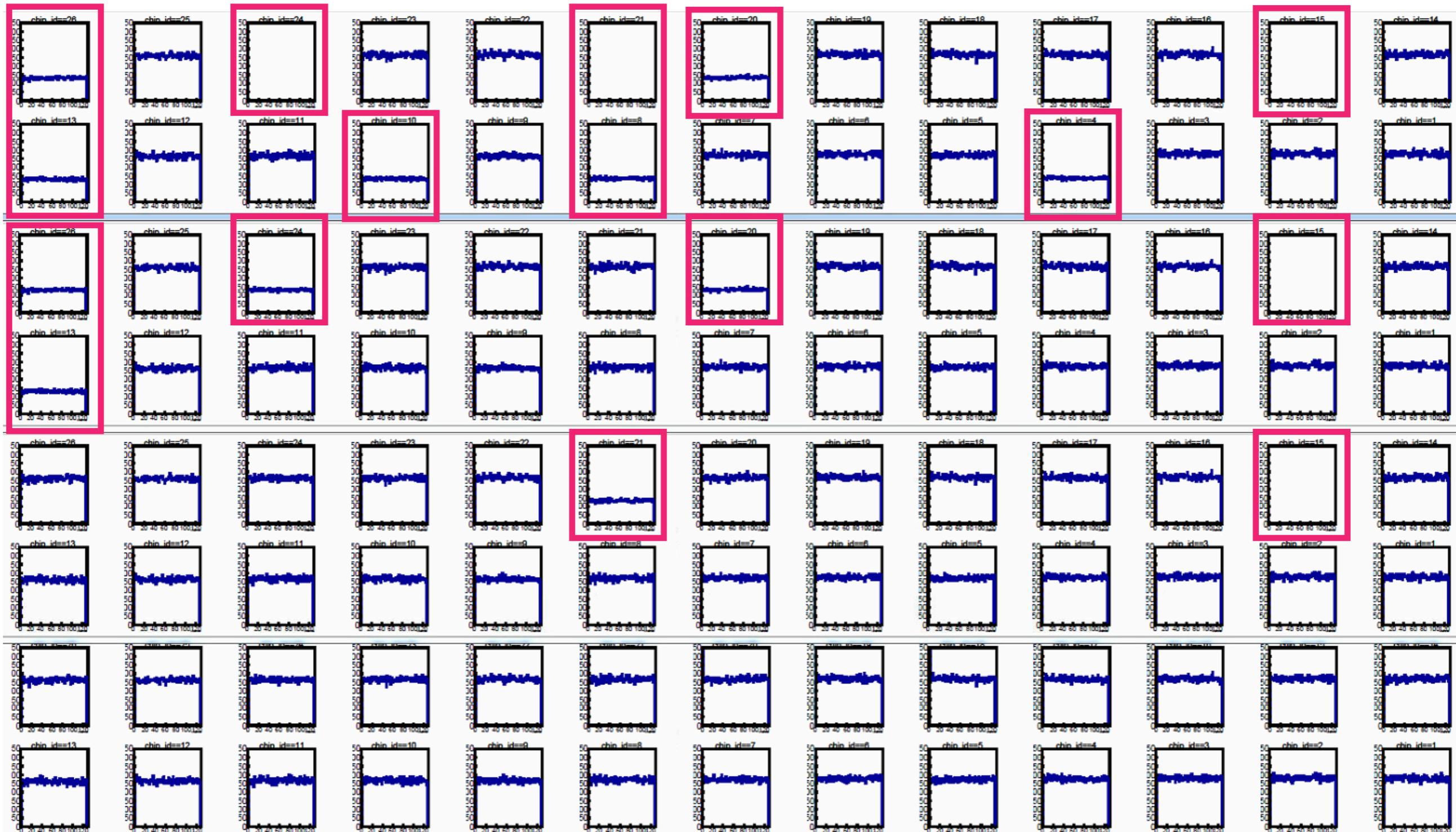
BEC test, BEC#1

Half-ladder performance : all chips are good without BEC
LVDS current : 1mA -> 2mA -> 4mA -> 8mA



BEC test, BEC#4

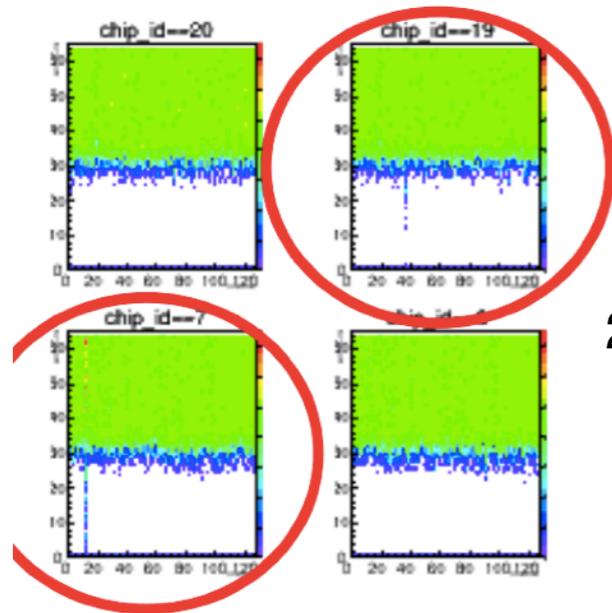
Half-ladder performance : all chips are good without BEC
LVDS current : 1mA -> 2mA -> 4mA -> 8mA



Channel classification : BNL



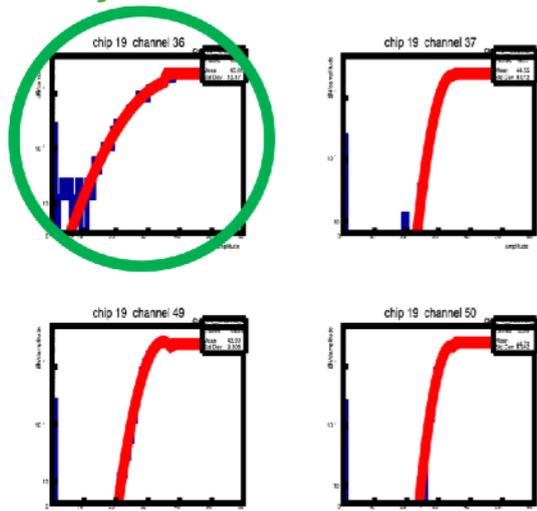
- Goal : try to classify good channel & bad channel.
- 2 algorithms so far, Taiwan & BNL.



We use the same data

2 noisy channel in this case

Noisy channel

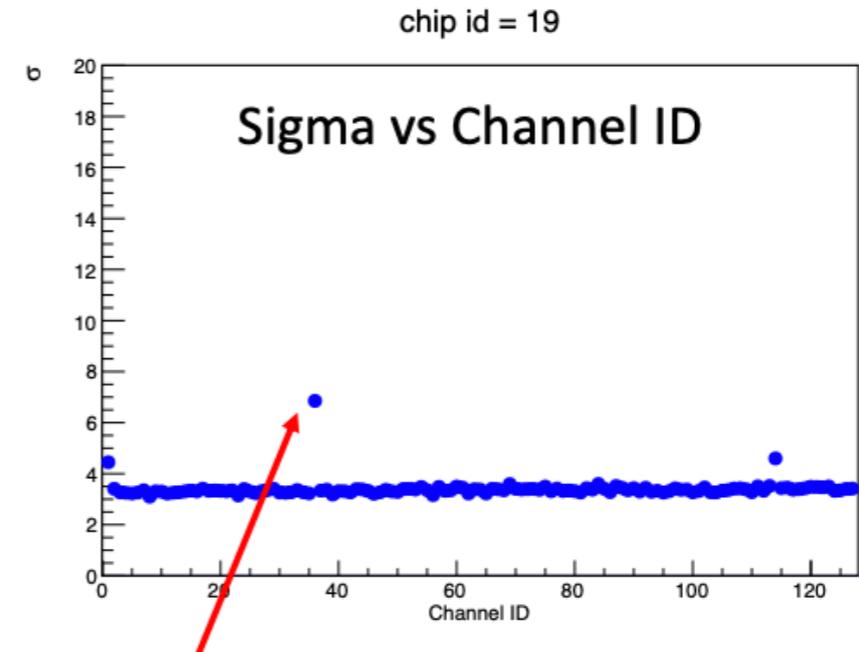


Every channel is fitted with gaussian
 X axis : ampl
 Y axis : entries

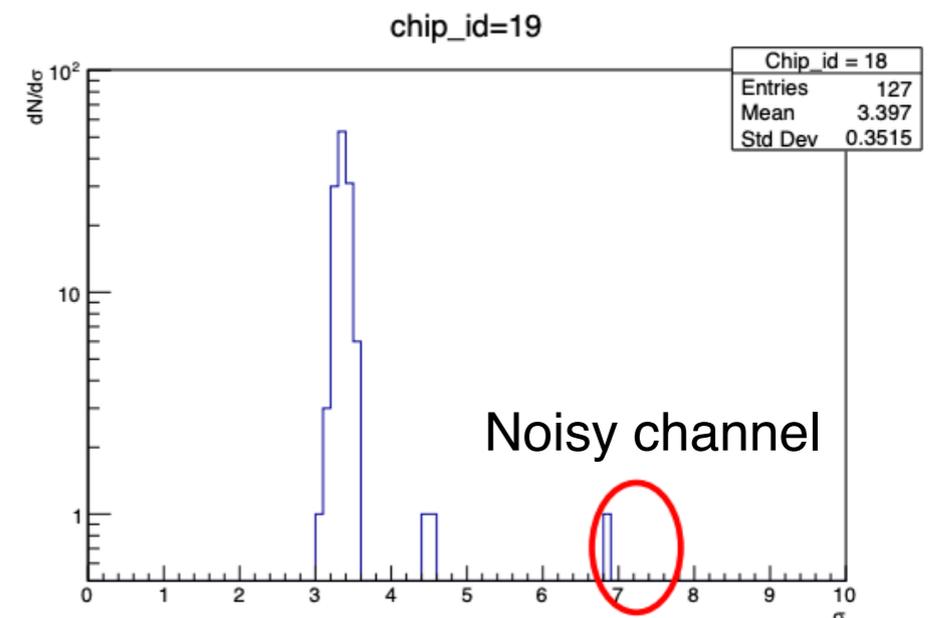
Fit function:

$$f(x) = \begin{cases} \text{Gaus}(x, \text{mean}, \text{sigma}), & x < a \\ \text{const}, & x \geq a \end{cases}$$

Require 20 runs of calibration test



Noisy channel

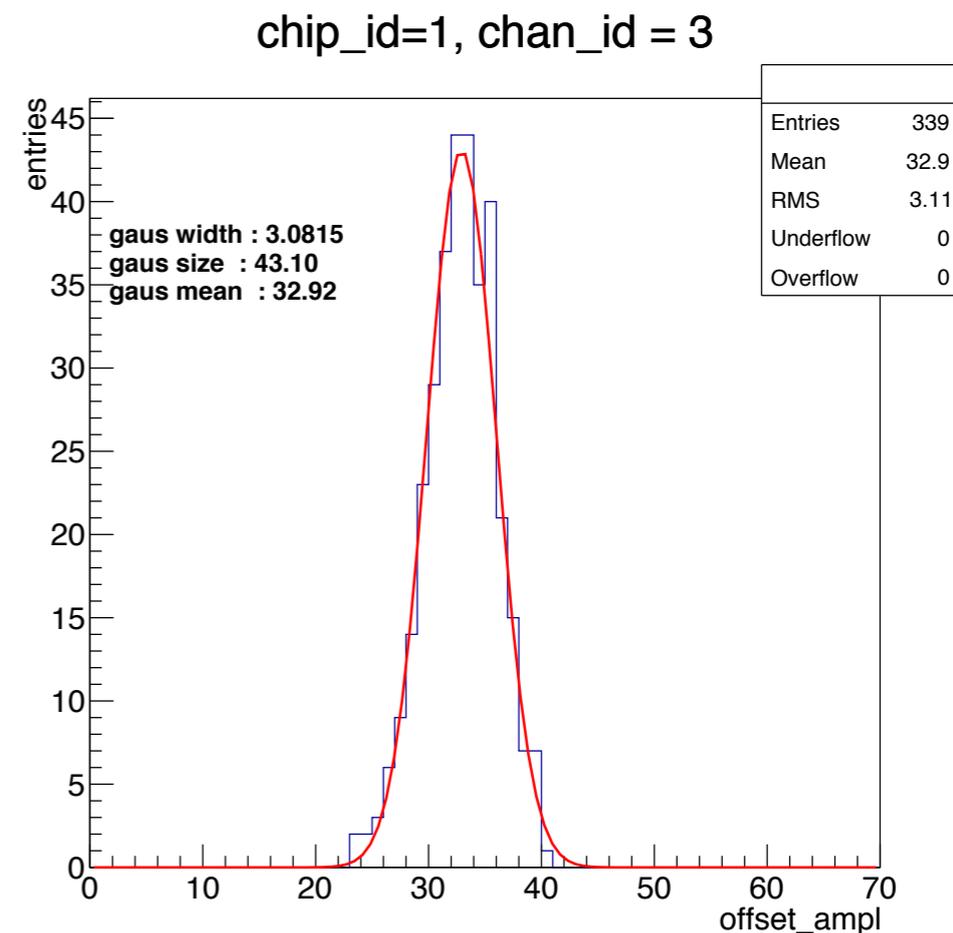
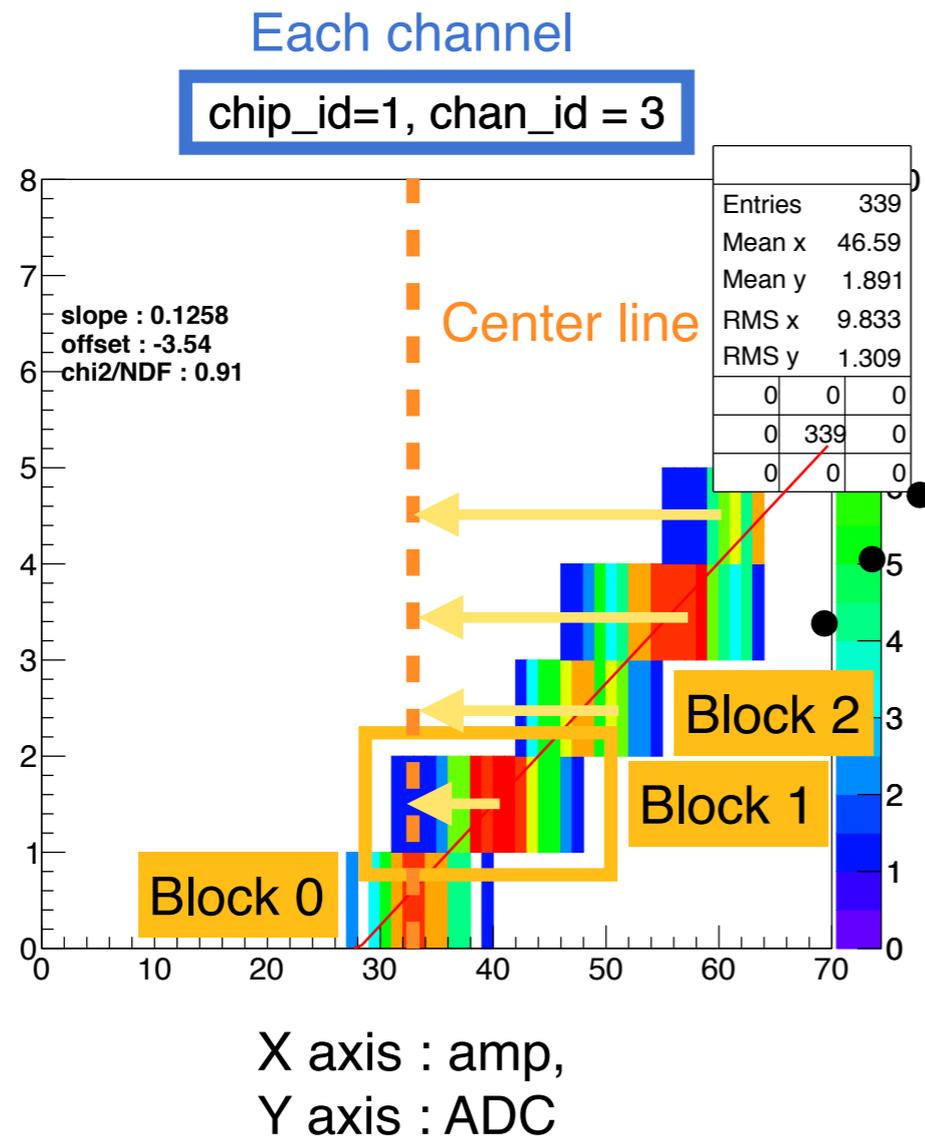


Noisy channel

Channel classification : Taiwan



- For each channel of each chip :
 - Center line : mean of events in “Block 0” (ADC==0)
 - Center of the rest blocks are panned to center line.
 - Amount of movement : Mean of each block - center line
 - Each event is filled in TH1F, and fit with gaussian.

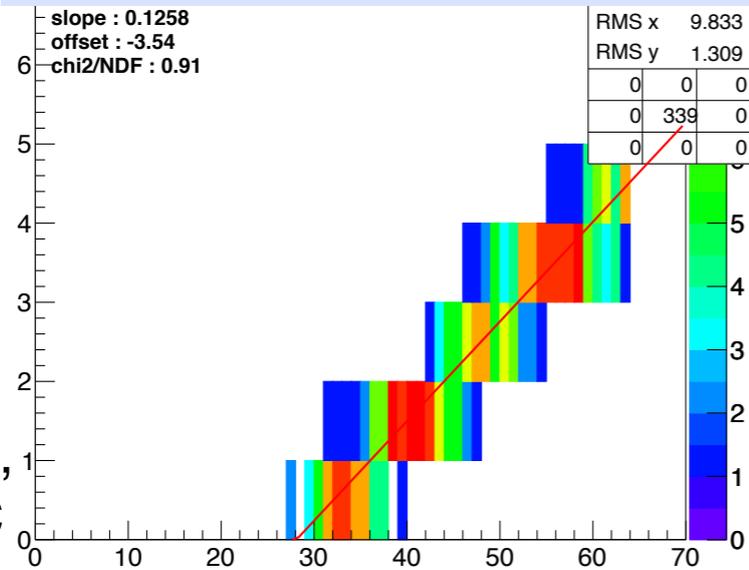


Channel classification : Taiwan



chip_id=1, chan_id = 3

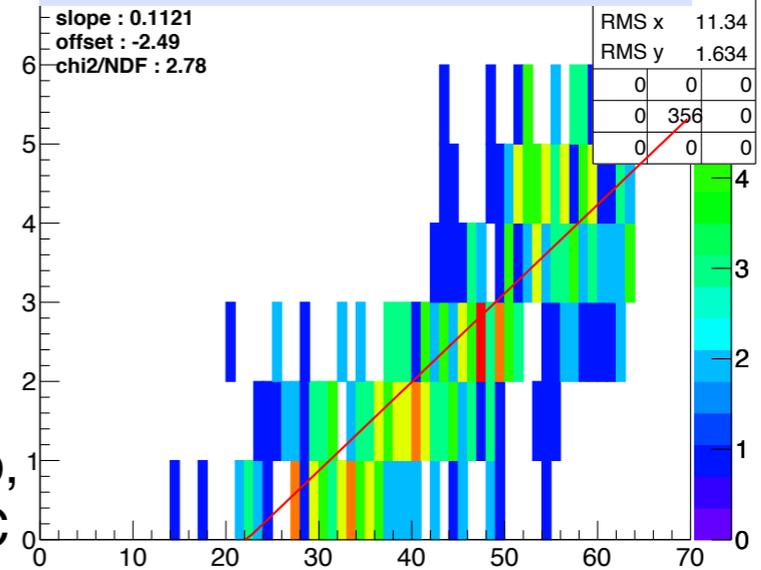
Example for functional channel



X axis : amp,
Y axis : ADC

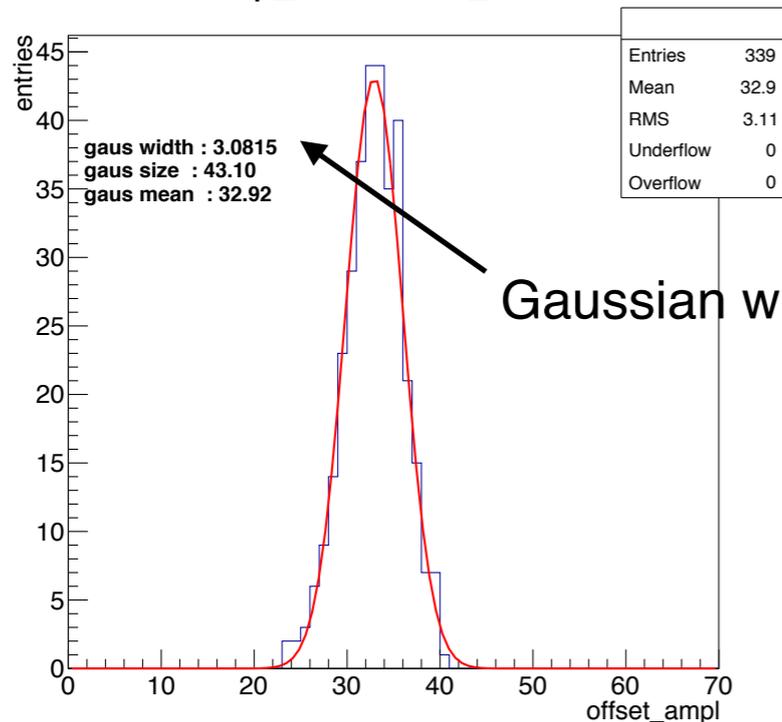
chip_id=7, chan_id = 12

Example for noisy channel



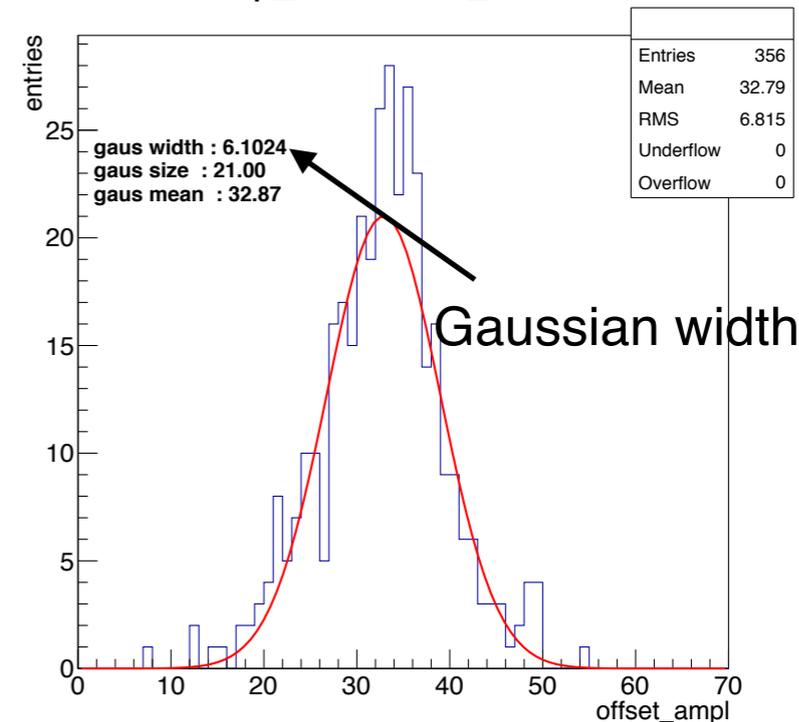
X axis : amp,
Y axis : ADC

chip_id=1, chan_id = 3



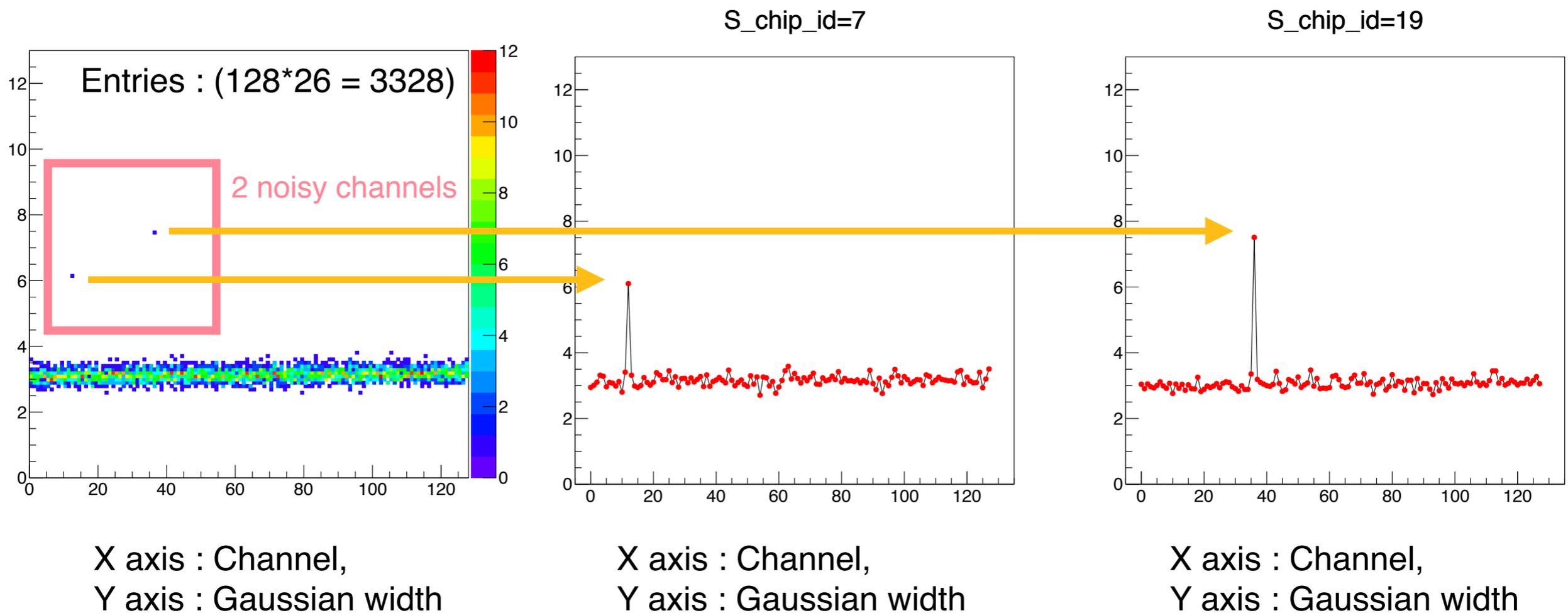
Gaussian width mostly < 4

chip_id=7, chan_id = 12



Gaussian width mostly > 4

Channel classification : Taiwan



Faster and with better separation power

Back up



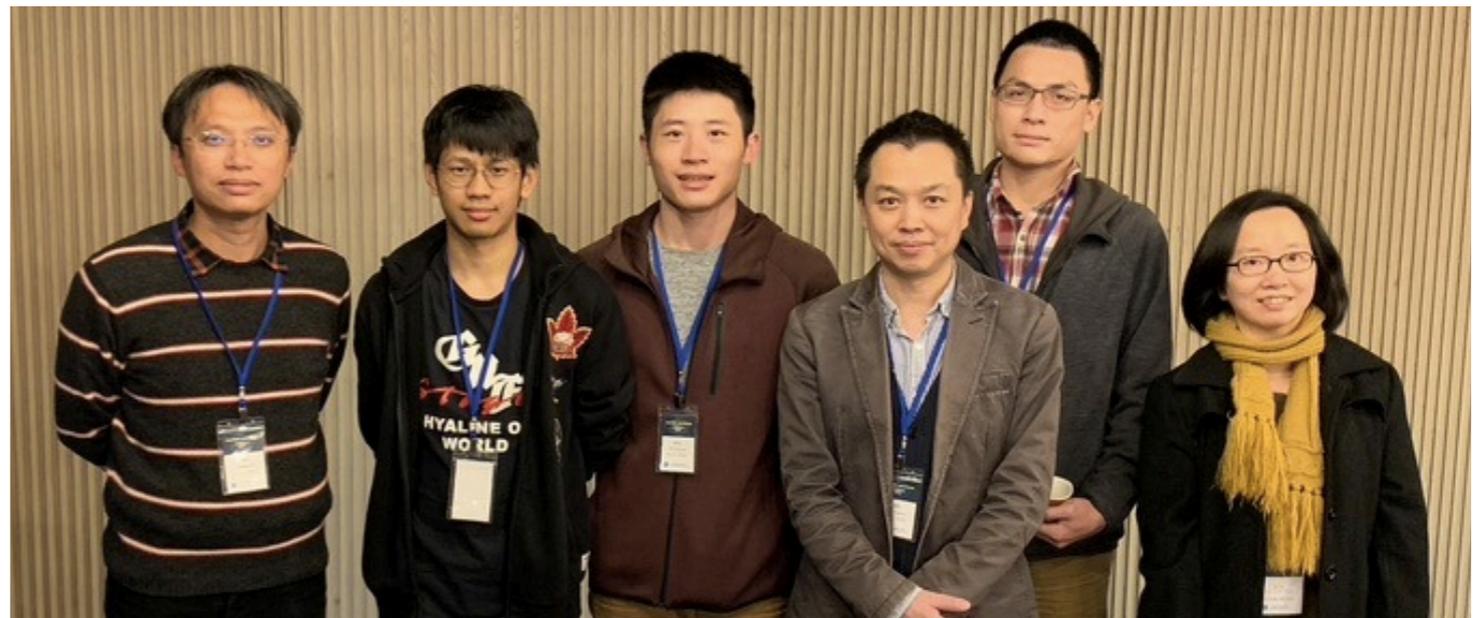
Taiwan INTT team



Ou-Wei Cheng

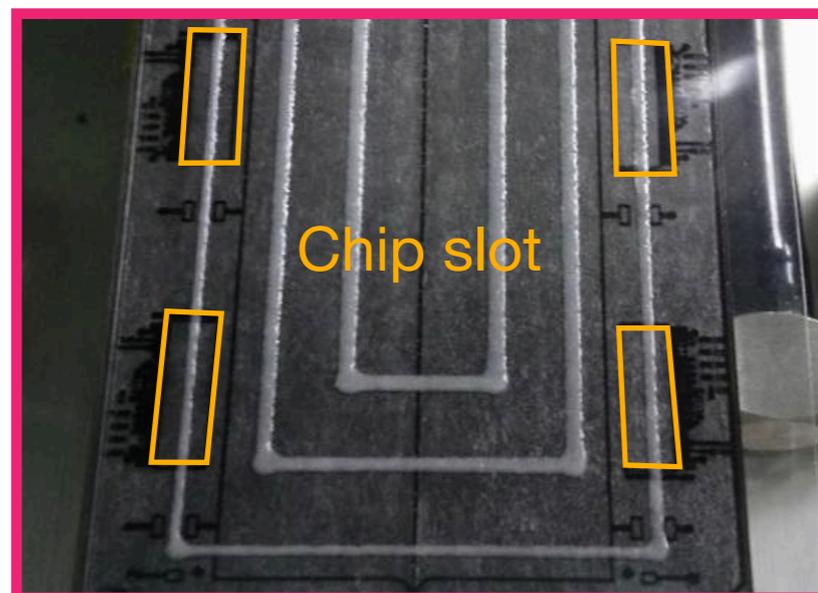


Kai-Yu Cheng

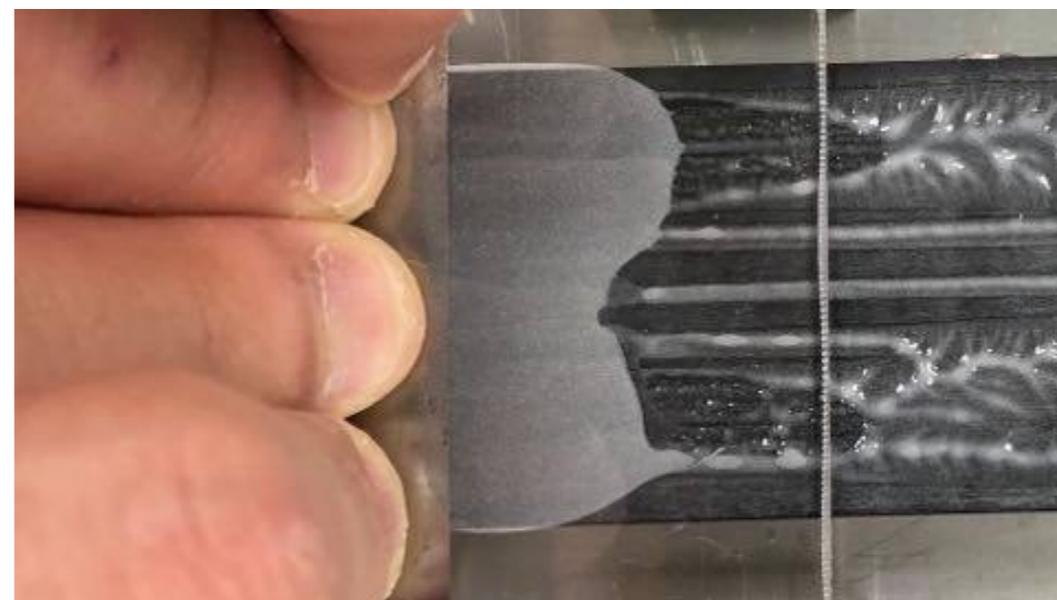


Chia-Ming Kuo Cheng-Wei Shih Lian-Sheng Tsai
Wei-Che Tang Rong-Shyang Lu Janny Huang

Regarding to the stave glue

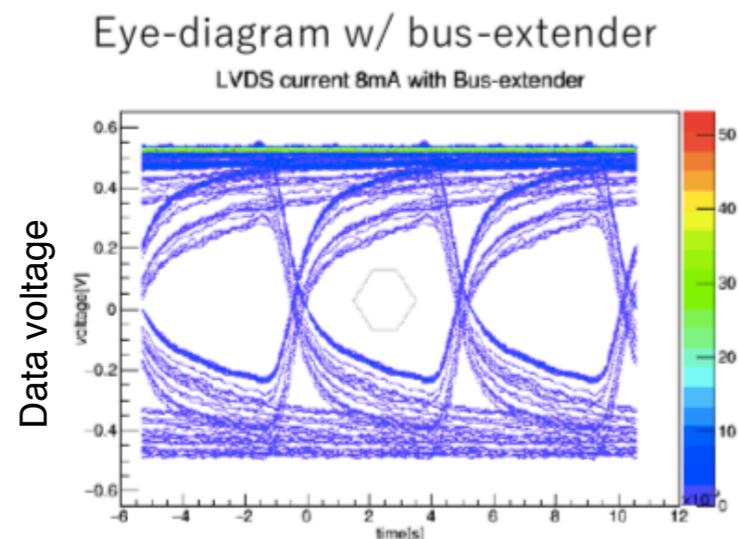
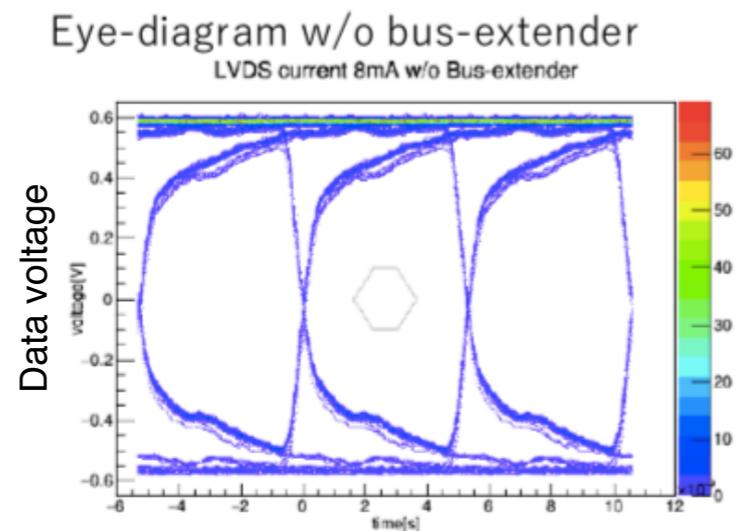


Two glue lines under chip



INTT DAQ problem

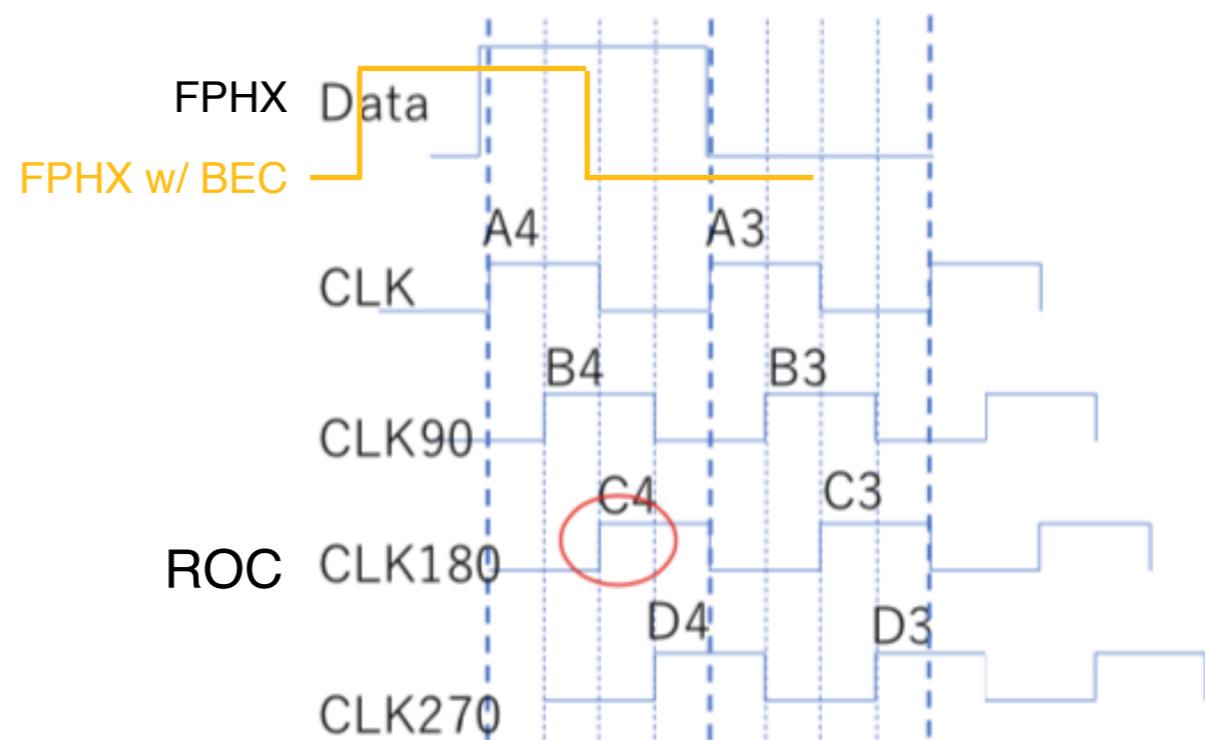
- General chip : output signal & clock. Example : CMS Pixel
 - Clock : to synchronize with following electronics
- INTT FPHX : output signal only



slow voltage rising rate

Goal : try to change the phase

FPHX - ROC synchronize method :
fix the phase at 180°



works in FVTX (short transmission cable)

Twist test status



- We first focused on barrel-1
- 23 barrel-1 staves in total (Batch-1 : 13, Batch-2 : 10)
 - 2 staves → failed in leakage test
 - 2 stave → ladder assembly.
 - 6 staves → twist test practice (all are bad in flatness)
- Remaining : 13 staves
 - 13 trials -> 13 failed
- We recorded the twist test for all staves and took photos after twist, photos and videos are in the [link](#).
- Leakage & submersion test for 8 batch-2 barrel-1 staves were performed after twist test → 1 passed
 - [link](#) of submersion test